# MSKSEMI 美森科













ESD

S

TSS

MOV

GDT

PLED

**BSS138P** 

**Product specification** 





#### **Features**

- 55V,0.3A, RDS(ON) =1.2Ω@VGS=10V
- Improved dv/dt capability
- Fast switching
- Green Device Available
- G-S ESD Protection Diode Embedded
- ESD protected up to 2KV

# **Applications**

- Motor Drive
- Power Tools
- LED Lighting

BVDSS	RDSON	ID
55V	1.2Ω	0.3A

#### **Reference News**

PACKAGE OUTLINE	N-Channel MOSFET	Marking
SOT-23	D ° S	ANW**

# Absolute Maximum Ratings (T<sub>A</sub>=25℃unless otherwise noted)

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	55	V
Vgs	Gate-Source Voltage	±20	V
L	Drain Current – Continuous (T <sub>A</sub> =25°C)	0.3	А
ID	Drain Current – Continuous (T₄=70°C)	0.16	А
Ірм	Drain Current – Pulsed1	0.8	А
D-	Power Dissipation (T <sub>A</sub> =25°C)	0.35	W
PD	Power Dissipation – Derate above 25°C	0.003	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	℃
TJ	Operating Junction Temperature Range -55 to 150		℃

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		357	°C/W



# Electrical Characteristics (T<sub>J</sub>=25 ℃, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions		Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , Ip=250uA	55			V
lpss	Drain-Source Leakage Current	V <sub>DS</sub> =55V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA
IDSS	Drain-Source Leakage Guirent	V <sub>DS</sub> =40V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			100	uA
Igss	Gate-Source Leakage Current	Vgs= ±20V , Vps=0V			±10	uA

#### **On Characteristics**

Process	Statio Drain Source On Begintance	Vgs= 10V , Ip=0.2A		1.2	1.5	Ω
RDS(ON)	Static Drain-Source On-Resistance	Vgs=4.5V , ID=0.1A		1.5	2.5	Ω
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>G</sub> S=V <sub>D</sub> S , I <sub>D</sub> =250uA	0.8	1.1	1.5	V
gfs	Forward Transconductance	Vps= 10V , Ip=0.2A		0.5		S

# **Dynamic and switching Characteristics**

Qg	Total Gate Charge <sup>2, 3</sup>		 3.7	
Qgs	Gate-Source Charge <sup>2,3</sup>	Vds=30V , Vgs=10V , Id=0.2A	 0.9	 nC
Qgd	Gate-Drain Charge <sup>2,3</sup>		 0.4	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2,3</sup>		 3	
Tr	Rise Time <sup>2,3</sup>	$V_{DD}$ =30 $V$ , $V_{GS}$ =10 $V$ , $R_{G}$ =6 $\Omega$	 5	
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2,3</sup>	lp=0.2A	 14	 ns
Tf	Fall Time <sup>2</sup> , <sup>3</sup>		 9	
Ciss	Input Capacitance		 25.5	
Coss	Output Capacitance	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , F=1MHz	 17	 pF
Crss	Reverse Transfer Capacitance		 7.8	

#### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V,Force Current			0.3	Α
Ism	Pulsed Source Current	VG-VD-0V, Force Current			0.6	Α
VsD	Diode Forward Voltage	Vgs=0V , Is=0.2A , Tյ=25°C			1.4	V
trr	Reverse Recovery Time	V <sub>R</sub> =50V, I <sub>S</sub> =0.2A		3.4		ns
Qrr	Reverse Recovery Charge	dI/dt= 100A/µs, Tյ=25°C		0.7		nC

#### Note

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width  $\leqq$  300us , duty cycle  $\,\leqq\,$  2%.
- 3. Essentially independent of operating temperature.

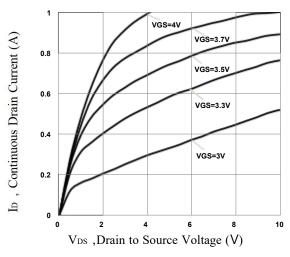


Fig. 1 Typical Output Characteristics

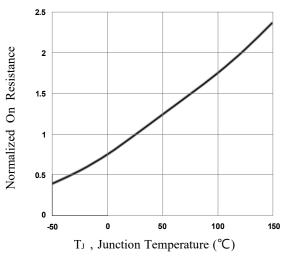


Fig. 3 Normalized RDSON vs.  $T_J$ 

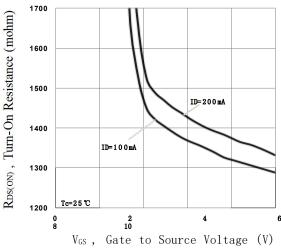


Fig. 5 Turn-On Resistance vs.  $V_{\text{GS}}$ 

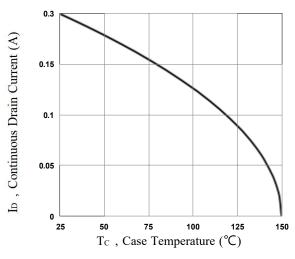


Fig. 2 Continuous Drain Current vs. Tc

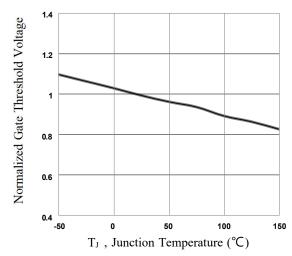


Fig. 4 Normalized  $V_{th}$  vs.  $T_J$ 

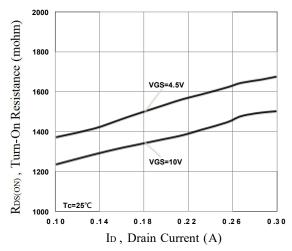


Fig. 6 Turn-On Resistance vs. ID

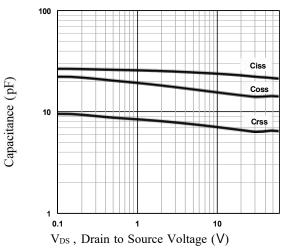
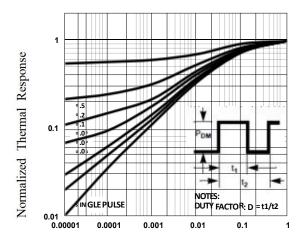


Fig. 7 Capacitance Characteristics



Square Wave Pulse Duration (s)

Fig. 9 Normalized Transient

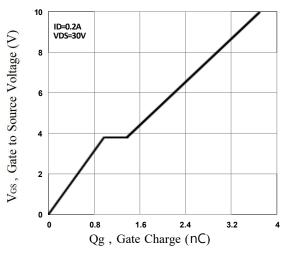
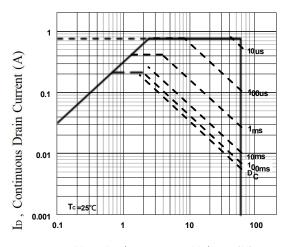


Fig. 8 Gate Charge Characteristics

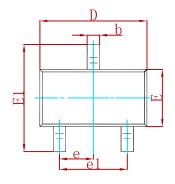


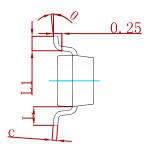
V<sub>DS</sub>, Drain to Source Voltage (V)

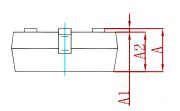
Fig. 10 Maximum Safe Operation Area



# PACKAGE MECHANICAL DATA

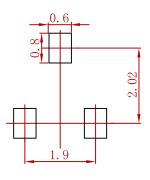






Complete	Dimensions In Millimeters		Dimension	nsions In Inches	
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
Е	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.03	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022	REF	
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

# **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters. 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

# **REELSPECIFICATION**

P/N	PKG	QTY
BSS138P	SOT-23	3000



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